Prober Mercury Probe

**Short description**: Mercury Probe is probing device to make rapid, non-destructive contact to a sample for electrical characterization. It makes the contact with the substrate with a concentric dot and ring mercury electrode and backside contact. Its primary application is semiconductor measurements, without performing the time consuming metallization and photolithographic processing. **It can be used to perform various C-V and I-V measurement on MOS samples, semiconductor doping etc.**

Center contact diameter : 907µm  
Stray capacitance : 1.8pF

**Localisation**: Welcome

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